## Notice of References Cited Application/Control No. 10/649,797 Examiner Wutchung Chu Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0058972	03-2003	lochi, Hitoshi	375/343
*	В	US-7,161,952	01-2007	Herrmann, Christoph	370/462
*	C	US-6,873,607	03-2005	Hamada et al.	370/321
*	D	US-6,112,085	08-2000	Garner et al.	455/428
*	E	US-5,204,976 ·	04-1993	Baldwin et al.	455/234.2
*	F	US-6,487,420	11-2002	Jonsson, Erik	455/522
*	G	US-2005/0174968	08-2005	Kitade et al.	370/335
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.